# PATENT COOPERATION TREATY

# **PCT**

# TRANSLATION INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY

(Chapter II of the Patent Cooperation Treaty)

(PCT Article 36 and Rule 70)

Applicant's or agent's file refere P37020-P0	nce	FOR FURTHER ACTIO	ON	See Form PCT/IPEA/416				
International application No.	]	International filing date (da	y/month/year)	Priority date (day/month/year)				
PCT/JP2004/01	7622	26.11.2004		01.12.2003				
International Patent Classificati	on (IPC) or nation	nal classification and IPC						
H01L21/3065								
Applicant								
MATSUSHITA ELECTRIC INDUSTRIAL CO., LTD.								
<ol> <li>This report is the international preliminary examination report, established by this International Preliminary Examining Authority under Article 35 and transmitted to the applicant according to Article 36.</li> </ol>								
2. This REPORT consist	s of a total of 6	5	sheets, including	this cover sheet.				
3. This report is also acc	ompanied by AN	NEXES, comprising:						
a. (sent to the	e applicant and to	o the International Bureau)	a total of 3	sheets, as follows:				
1 1 2 1				mended and are the basis for this report and/or				
	sheets containing rectifications authorized by this Authority (see Rule 70.16 and Section 607 of the Administrative Instructions).							
sheets which supersede earlier sheets, but which this Authority considers contain an amendment that goes beyond the disclosure in the international application as filed, as indicated in item 4 of Box No. I and the Supplemental								
Box.								
b (sent to th	e International Bi	ureau only) a total of (indic	ate type and number	of electronic carrier(s))				
, containing a sequence listing and/or tables								
related thereto, in computer readable form only, as indicated in the Supplemental Box Relating to Sequence Listing (see Section 802 of the Administrative Instructions).								
4. This report contains in	dications relating	g to the following items:						
Box No. I	Basis of the re	eport	l					
Box No. II	Priority							
Box No. III	Non-establish	nment of opinion with regar	th regard to novelty, inventive step and industrial applicability					
Box No. IV	Lack of unity	of invention						
Box No. V								
Box No. VI								
Box No. VII	Certain defect	plication						
Box No. VIII Certain observations on the international application								
Date of submission of the dema	nd	Date	of completion of thi	s report				
Name and mailing address of the IPEA/JP			Authorized officer					
Facsimile No.		Telep	Telephone No.					

# INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY

International application No.

PCT/JP2004/017622

Box	No. I	Basis of the report							
1.		n regard to the language, this report is based on the internationated under this item.	onal application in the language in	which it was filed, unless otherwise					
	This report is based on translations from the original language into the following language which is the language of a translation furnished for the purposes of:								
		international search (Rule 12.3 and 23.1(b))							
		publication of the international application (Rule 12.	4)						
		international preliminary examination (Rule 55.2 and	Mor 55.3)						
2.	2. With regard to the <b>elements</b> of the international application, this report is based on (replacement sheets which have been furnished to the receiving Office in response to an invitation under Article 14 are referred to in this report as "originally filed" and are not annexed to this report):								
		the international application as originally filed/furnished							
	$\bowtie$	the description:							
		pages		as originally filed/furnished					
		pages*	received by this Authority on						
		pages*	_ received by this Authority on .						
	$\boxtimes$	the claims:							
		nos. 2-8,10-12,14,16-19		as originally filed/furnished					
		nos.*	as amended (together	r with any statement) under Article 19					
		nos.* _1,9,15	_ received by this Authority on	29.09.2005					
		nos.*	received by this Authority on						
	$\boxtimes$	the drawings:							
		sheets 1-7		as originally filed/furnished					
		sheets*							
		a sequence listing and/or any related table(s) – see Suppler							
3.	$\boxtimes$	The amendments have resulted in the cancellation of:	he amendments have resulted in the cancellation of:						
		the description, pages							
		the claims, nos. 13							
		the drawings, sheets/figs							
		the sequence listing (specify):							
		any table(s) related to sequence listing (specify):							
4.		. ,	is report has been established as if (some of) the amendments annexed to this report and listed below had not been made, since y have been considered to go beyond the disclosure as filed, as indicated in the Supplemental Box (Rule 70.2(c)).						
		the description, pages							
		the claims, nos.							
		the drawings, sheets/figs							
		the sequence listing (specify):	the sequence listing (specify):						
		any table(s) related to sequence listing (specify):							
*	If item 4 applies, some or all of those sheets may be marked "superseded."								

#### INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY

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#### 2. Citations and explanations (Rule 70.7)

The following documents are cited in the international search report.

- Document 1: JP 2002-542623 A (Lam Research Corp.), 10

  December 2002, paragraphs [0026] to [0033]
- Document 2: JP 2003-303812 A (Matsushita Electric Industrial Co., Ltd.), 24 October 2003, paragraph [0094] and fig. 1
- Document 3: JP 2000-299310 A (Denso Corp.), 24 October 2000, paragraphs [0063] to [0072] and fig. 7
- Document 4: WO 2003-030239 Al (Sumitomo Precision Products Co., Ltd.), 10 April 2003, paragraph [0094] and fig. 1
- Document 5: JP 2001-284283 A (Hitachi, Ltd.), 12 October 2001, paragraph [0098]

## Claims 1 to 10, 18 and 19

Document 1 discloses a method for plasma etching a silicon object within a processing chamber, wherein trenches are formed in the aforementioned silicon object by introducing an etching gas that contains  $O_2$ ,  $SF_6$ , He or  $Cl_2$  into the interior of the aforementioned processing chamber and then converting the aforementioned etching

Box No. V Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement

gas into a plasma by means of a TCP device.

Meanwhile, document 2 indicates that high-frequency power with a frequency in the range of 50 kHz to 500 MHz is applied to the coil of the TCP device. Such being the case, it would have been obvious to a person skilled in the art to configure so that high-frequency power with a frequency in the range of 50 kHz to 500 MHz is applied to the coil of the TCP device in the invention disclosed in document 1.

Furthermore, a person skilled in the art could set an appropriate frequency for the high-frequency power, regardless of the type of plasma etching gas that is used.

Such being the case, the inventions set forth in claims 1 to 10, 18 and 19 do not involve an inventive step.

## Claims 11, 12 and 14

Document 1 discloses a method for plasma etching a silicon object within a processing chamber, wherein trenches are formed in the aforementioned silicon object by introducing an etching gas that contains  $O_2$ ,  $SF_6$ , He or  $Cl_2$  into the interior of the aforementioned processing chamber and then converting the aforementioned etching gas into a plasma by means of a TCP device.

Meanwhile, document 2 indicates that high-frequency power with a frequency in the range of 50 kHz to 500 MHz is applied to the coil of the TCP device.

Furthermore, document 3 discloses a trench formation method wherein trenches are formed by means of  $SF_6$  gas, and then a protective film is formed upon the side walls of the trenches by means of a gas that

Box No. V Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement

contains  $C_4F_8$ .

In addition, document 4 discloses a feature wherein trenches are formed by means of a gas system that contains  $SF_6$  and  $C_4F_8$ , which is a gas for forming a protective film.

Documents 1, 3 and 4 all pertain to the same technical feature; i.e., forming trenches on a silicon substrate. Therefore, it is considered to have been easy for a person skilled in the art to conceive of forming trenches by means of the gas disclosed in document 1, which contains  $O_2$ ,  $SF_6$ , He or  $Cl_2$ , and then forming both trenches and protective films by means of the gas system disclosed in document 4, which contains  $SF_6$  and  $C_4F_8$ , in the light of the disclosures in document 3.

Furthermore, in the light of the disclosure in document 2 it would have been obvious to a person skilled in the art to configure so that high-frequency power with a frequency in the range of 50 kHz to 500 MHz is applied to the coil of the TCP device in the invention disclosed in document 1.

Such being the case, the inventions set forth in claims 11, 12 and 14 do not involve an inventive step.

## Claims 15 to 17

Document 5 discloses a method for plasma etching a silicon object by means of  $Ar/CF_4$ . Therein, it would have been easy for a person skilled in the art to conceive of increasing the precision of the etching depth by adjusting the flow rate of the Ar or the  $CF_4$  and by using a gas other than  $CF_4$  in order to decrease the etching speed.

Such being the case, the inventions set forth in

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International application No.
PCT/JP2004/017622

Box No. V	Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement							
cla							inventive	step.
1								